

Mag Layers USA, INC

Specification Sheet

P/N: MSCDRI-4D28C-SERIES-RU

Products:

Certifications:

Molded Power Chokes

Multilayer Chip Inductors

Lan Transformer

RF Passive / Antennas

<u>Automotive</u>

<u>ISO9001</u>

IATF16949

ISO14001

QC080000

US Office

5406 Bolsa Ave., Huntington Beach, CA 92649 (714) 898-8377

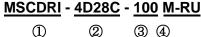
Contact Us

www.maglayersusa.com info@maglayersusa.com

SCOPE :

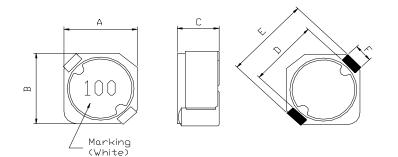
This specification applies to the Pb Free high current type SMD inductors for MSCDRI-4D28C-SERIES

PRODUCT INDENTIFICATION



- ① Product Code
- ② Dimensions Code
- ③ Inductance Code
- Tolerance Code

(1) SHAPES AND DIMENSIONS



A: 5.10 Max. mm B: 5.10 Max. mm C: 3.00 Max. mm D: 4.40 Typ. mm E: 6.20 Max. mm F: 1.40 Typ. mm

(2) ELECTRICAL SPECIFICATIONS SEE TABLE 1

TEST INSTRUMENTS

- L : HP 4284A PRECISION LCR METER (or equivalent)
- RDC : CHROMA MODEL 16502 MILLIOHMMETER (or equivalent)

(3) CHARACTERISTICS

- (3)-1 Ambient temperature $+60^{\circ}$ C Max.
- (3)-2 Operate temperature range $-40^{\circ}C \sim +125^{\circ}C$ (Including self temp. rise)
- (3)-3 Storage temperature range $-40^{\circ}C \sim +125^{\circ}C$



TABLE 1

MAGLAYERS	Inductance	Percent	Test	Resistance	Rated DC Current	Marking	
PT/NO.	L(µH)	Tolerance	Frequency	RDC(Ω)Max.	IDC(A)	Marking	
MSCDRI-4D28C-1R1 -RU	1.1	N	100kHz/0.25V	22m	3.80	1R1	
MSCDRI-4D28C-2R0 -RU	2.0	M,N	100kHz/0.25V	29m	2.60	2R0	
MSCDRI-4D28C-3R2 -RU	3.2	N	100kHz/0.25V	42m	2.30	3R2	
MSCDRI-4D28C-4R7 -RU	4.7	M,N	100kHz/0.25V	63m	1.80	4R7	
MSCDRI-4D28C-6R3 -RU	6.3	N	100kHz/0.25V	94m	1.30	6R3	
MSCDRI-4D28C-100 -RU	10	M,N	100kHz/0.25V	0.106	1.26	100	
MSCDRI-4D28C-150 -RU	15	M,N	100kHz/0.25V	0.137	1.05	150	
MSCDRI-4D28C-220 -RU	22	M,N	100kHz/0.25V	0.207	0.85	220	
MSCDRI-4D28C-330 -RU	33	M,N	100kHz/0.25V	0.331	0.70	330	
MSCDRI-4D28C-470 -RU	47	M,N	100kHz/0.25V	0.510	0.54	470	
MSCDRI-4D28C-680-	68	M,N	100kHz/0.25V	0.625	0.49	680	
MSCDRI-4D28C-101 -RU	100	M,N	100kHz/0.25V	0.948	0.40	101	

% □ specify the inductance tolerance,M(±20%),N(±30%)

<code>%IDC</code> : Based on inductance change (\triangle L/Lo : drop 35% max) @ ambient temp. 25°C and

Based on temperature rise ($\triangle T$: 40°C TYP.)



(4) RELIABILITY TEST METHOD

MECHANICAL

TEST ITEM	SPECIFICATION	TEST DETAILS			
Substrate bending	∆L/Lo≦±5%	The sample shall be soldered onto the printed circuit board			
		in figure 1 and a load applied unitil the figure in the arrow			
	There shall be	direction is made approximately 3mm.(keep time 30 seconds)			
	no mechanical	PCB dimension shall the page 7/9			
	damage or elec-	F(Pressurization)			
	trical damege.	Ţ,			
		R340			
		PRESSURE ROD figure-1			
Vibration	∆L/Lo≦±5%	The sample shall be soldered onto the printed circuit board			
		and when a vibration having an amplitude of 1.52mm			
	There shall be	and a frequency of from 10 to 55Hz/1 minute repeated should			
	no mechanical	be applied to the 3 directions (X,Y,Z) for 2 hours each.			
	damage.	(A total of 6 hours)			
Solderability	New solder	Flux (rosin, isopropyl alcohol{JIS-K-1522}) shall be coated			
	More than 90%	over the whole of the sample before hard, the sample shall			
		then be preheated for about 2 minutes in a temperature of			
		130 \sim 150 $^\circ\!\mathrm{C}$ and after it has been immersed to a depth 0.5mm			
		below for 3 ± 0.2 seconds fully in molten solder M705 with			
		a temperature of 245±5℃.			
		More than 90% of the electrode sections shall be couered			
		with new solder smoothly when the sample is taken out of			
		the solder bath.			



MECHANICAL

TEST ITEM		SPECIFICATION					
TEST ITEM Resistance to Soldering heat (reflow soldering)	There shall be no damage or problems.	SPECIFICATION Temperature profile of reflow soldering 300 soldering 250 (Peak temperature 260±3℃ 10 sec 30 sec Mn 150 150 150 150 150 150 150 150 100 150 200 (201° ℃) Slow cooling (Stored at room temperature) 50 2 min 2 min 10 sect 2 min 10 sect 2 min 10 sect 2 min 10 sect 2 min 0 3 sect 2 min 3 sect 2 min					
		condition shown in the above profile for 1 time. The specimen shall be stored at standard atmospheric conditions for 1 hour, after which the measurement shall be made.					

ELECTRICAL

TEST ITEM	SPECIFICATION	TEST DETAILS
Insulation	There shall be	DC 100V voltage shall be applied across this sample of top
resistance	no other	surface and the terminal.
	damage or	The insulation resistance shall be more than 1 × $10^8 \Omega$.
	problems.	
Dielectric	There shall be	AC 100V voltage shall be applied for 1 minute acrosset the top
withstand	no other	surface and the terminal of this sample
voltage	damage or	
	problems.	
Temperature	<u> ∆L/L20℃≦±10%</u>	The test shall be performed after the sample has stabilized in
characteristics	0~2000 ppm/℃	an ambient temperature of -20 to +85 $^\circ\!\!{ m C}$,and the value
		calculated based on the value applicable in a normal
		temperature and narmal humidity shall be $ riangle L/L20^{\circ}C \leq \pm 10\%$.



ENVIROMENT CHARACTERISTICS

TEST ITEM		SPECIFICATION					
High temperature	∆L/Lo≦±5%	\triangle L/Lo \leq ±5% The sample shall be left for 96±4 hours in an atmospere with					
storage		a tempe	a temperature of 85±2 $^\circ\!\!\mathbb{C}$ and a normal humidity.				
	There shall be	Upon co	Upon completion of the measurement shall be made after the				
	no mechanical	sample	sample has been left in a normal temperature and normal				
	damage.	humidit	humidity for 1 hour.				
Low temperature	∆L/Lo≦±5%	The sample shall be left for 96±4 hours in an atmosphere with					
storage		a tempe	a temperature of -25±3℃.				
	There shall be	Upon co	omple	tion of the test, the mea	surement shall be mad	e	
	no mechanical	after the	after the sample has been left in a normal temperature and				
	damage.	normal	normal humidity for 1 hour.				
Change of	∆L/Lo≦±5%	The san	The sample shall be subject to 5 continuos cycles, such as shown				
temperature		in the ta	in the table 2 below and then it shall be subjected to standard				
	There shall be	atmosp	heric (conditions for 1 hour, af	ter which measuremen	t	
	no other dama-	shall be	made				
	ge of problems						
				table 2			
				Temperature	Duration		
			1	— 25±3 ℃	30 min.		
				(Themostat No.1)			
			2	Standard	No.1→No.2		
				atmospheric			
			3	85±2℃	30 min.		
				(Themostat No.2)			
			4	Standard	No.2→No.1		
				atmospheric			
Moisuture storage	∆L/Lo≦±5%	The san	nple s	hall be left for 96±4 hou	rs in a temperature of		
-		$40\pm2^{\circ}$ and a humidity(RH) of $90\sim95\%$.					
	There shall be	Upon completion of the test, the measurement shall be made					
	no mechanical		after the sample has been left in a normal temperature and				
	damage.		normal humidity more than 1 hour.				
Test conditions :	1	I					
The s	ample shall be reflor	w soldered	d onto	the printed circuit boar	d in every test.		
	-			-	-		

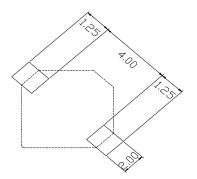


(5) LAND DIMENSION (Ref.)

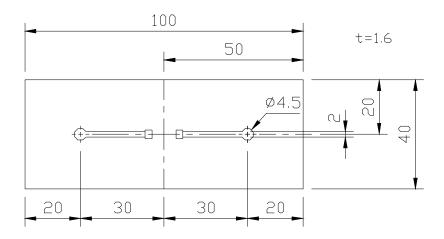
PCB: GLASS EPOXY t=1.6mm

(5)-1 LAND PATTERN DIMENSIONS

(STANDARD PATTERN) Unit : mm

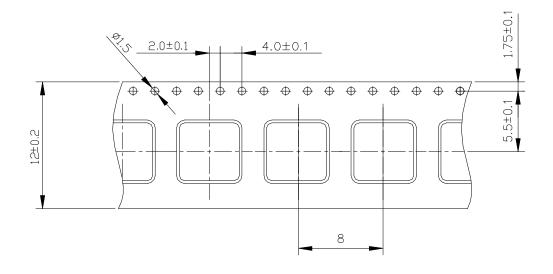


(5)-2 SUBSTRATE BENDING TEST BENDING TEST BOARD



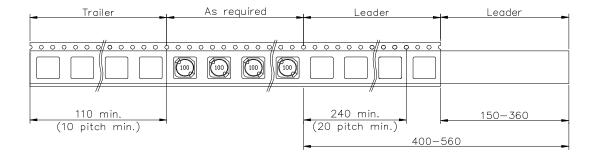


(6) PACKAGING (6)-1 CARRIER TAPE DIMENSIONS (mm)



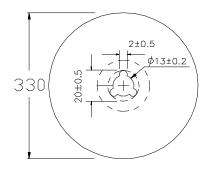
(6)-2 TAPING DIMENSIONS (mm)

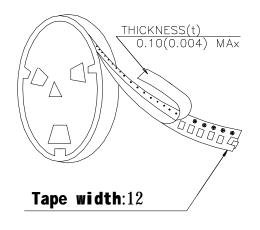






(6)-3 REEL DIMENSIONS (mm)





(6)-4 QUANTITY

2000pcs/Reel

The products are packaged so that no damage will be sustained.

